Power LDMOS transistor

Rev. 2 — 5 March 2014

Product data sheet

1. Product profile

1.1 General description

100 W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 2500 MHz to 2700 MHz.

Table 1. Typical performance

Typical RF performance at T_{case} = 25 °C in a common source class-AB production test circuit.

Test signal	f	I _{Dq}	V _{DS}	P _{L(AV)}	Gp	η_D	ACPR _{5M}
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	2500 to 2700	900	28	25	17	28	-32 <u>[1]</u>

[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF per carrier; 5 MHz carrier spacing.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low thermal resistance providing excellent thermal stability
- Designed for broadband operation (2500 MHz to 2700 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

 RF power amplifiers for base stations and multi carrier applications in the 2500 MHz to 2700 MHz frequency range



2. Pinning information

Pin	Description		Simplified outline	Graphic symbol
1	drain			
2	gate			1 لـــا
3	source [1]		2 – F 3 sym112	

[1] Connected to flange.

3. Ordering information

Table 3. Ordering information				
Type number Package				
	Name	Description	Version	
BLF8G27LS-100	-	earless flanged ceramic package; 2 leads	SOT502B	

4. Limiting values

Table 4.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature	[1]	-	225	°C

[1] Continuous use at maximum temperature will affect the reliability, for details refer to the on-line MTF calculator.

5. Thermal characteristics

Table 5.	Thermal characteristics				
Symbol	Parameter	Conditions	Тур	Unit	
R _{th(j-c)}	thermal resistance from junction to case	$T_{case} = 80 \text{ °C}; P_{L} = 100 \text{ W}$	0.292	K/W	

6. Characteristics

Table 6. DC characteristics

 $T_i = 25 \ ^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{(BR)DSS}	drain-source breakdown voltage	$V_{GS} = 0 V; I_D = 1 mA$	65	-	-	V
V _{GS(th)}	gate-source threshold voltage	V _{DS} = 10 V; I _D = 153 mA	1.5	1.9	2.3	V
I _{DSS}	drain leakage current	V _{GS} = 0 V; V _{DS} = 28 V	-	-	4.2	μA
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 V;$ $V_{DS} = 10 V$	-	29	-	A
I _{GSS}	gate leakage current	V _{GS} = 11 V; V _{DS} = 0 V	-	-	420	nA
g _{fs}	forward transconductance	V _{DS} = 10 V; I _D = 153 mA	-	1.27	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 V;$ $I_D = 5.35 A$	-	0.1	-	Ω

Table 7. RF characteristics

Test signal: 2-carrier W-CDMA; 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on the CCDF; $f_1 = 2502.5$ MHz; $f_2 = 2507.5$ MHz; $f_3 = 2692.5$ MHz; $f_4 = 2697.5$ MHz; RF performance at $V_{DS} = 28$ V; $I_{Dq} = 900$ mA; $T_{case} = 25$ °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gp	power gain	$P_{L(AV)} = 25 W$	15.8	17	-	dB
η_D	drain efficiency	$P_{L(AV)} = 25 W$	23	28	-	%
RL _{in}	input return loss	$P_{L(AV)} = 25 W$	-	-12	-8	dB
$ACPR_{5M}$	adjacent channel power ratio (5 MHz)	$P_{L(AV)} = 25 W$	-	-32	-27	dBc

7. Test information

7.1 Ruggedness in class-AB operation

The BLF8G27LS-100 is capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: V_{DS} = 28 V; I_{Dq} = 900 mA; P_L = 100 W (CW); f = 2500 MHz.

7.2 Impedance information

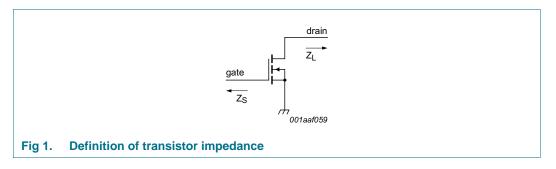
Table 8.Typical impedance

Measured load-pull data; $V_{DS} = 28$ V; $I_{Dq} = 900$ mA.

f	Z _S [1]	Z _L [1]
(MHz)	(Ω)	(Ω)
2500	1.2 – j4.6	2.7 – j2.7
2600	2.3 – j5.5	2.5 – j2.5
2700	3.8 – j5.2	2.1 – j2.6

[1] Z_S and Z_L defined in Figure 1.

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7.3 Test circuit information

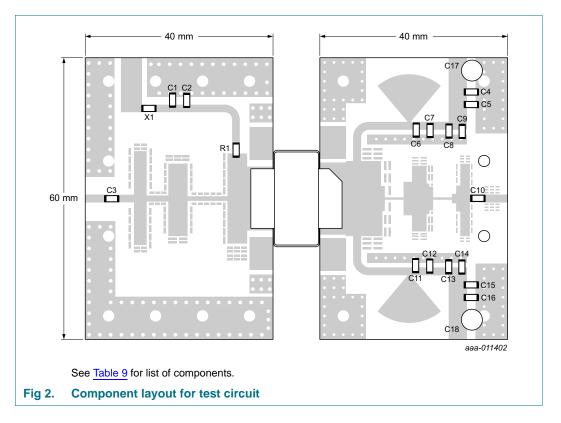


Table 9.List of components

See <u>Figure 2</u> for component layout.

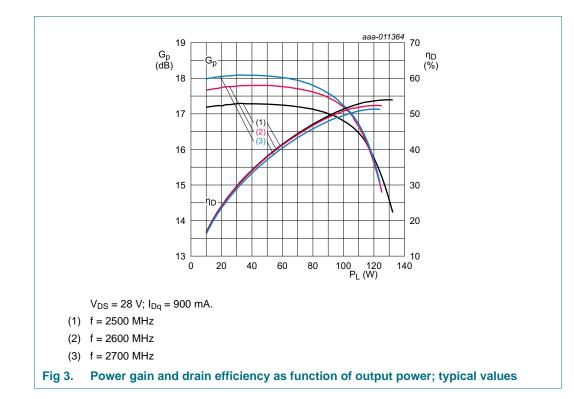
The used PCB (Printed-Circuit Board) material is Rogers RO4350B with a thickness of 0.762 mm.

Component	Description	Value	Remarks
C1, C2, C3, C6, C7, C10, C11, C12	multilayer ceramic chip capacitor	22 pF	ATC600F
C4, C5, C8, C9, C13, C14, C15, C16	multilayer ceramic chip capacitor	4.7 μF, 50 V	Murata
C17, C18	electrolytic capacitor	2200 μF; 50 V	
R1	chip resistor	9.1 Ω	SMD 0603
X1	copper foil strip	-	

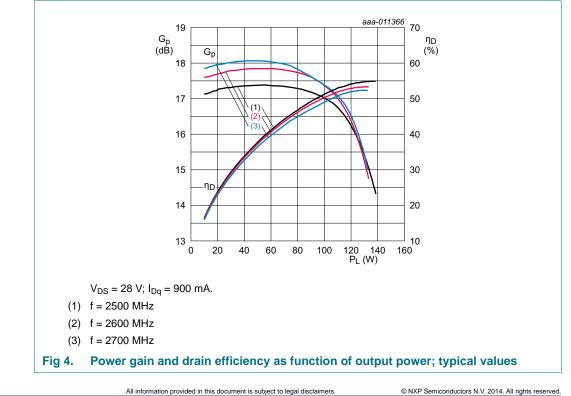
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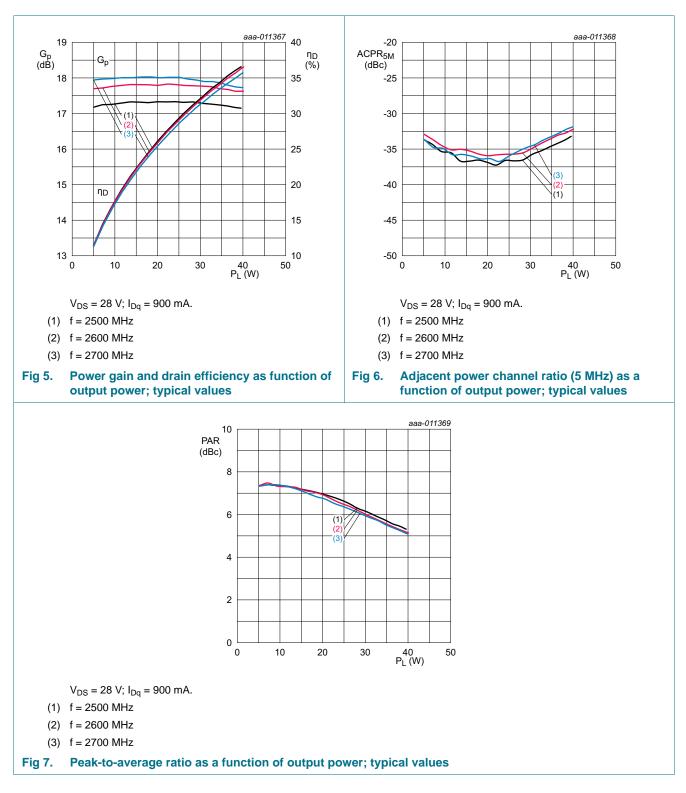
7.4.1 CW





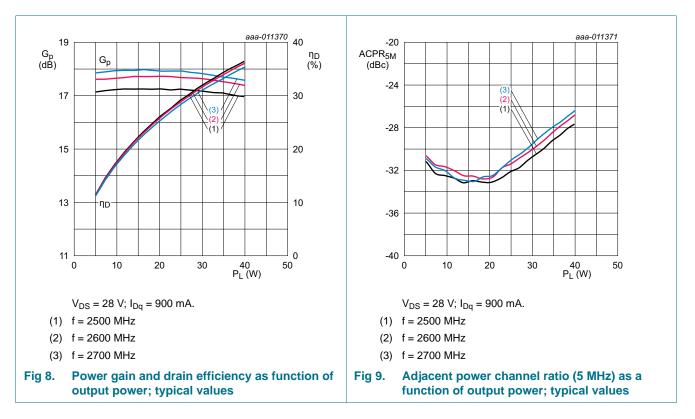


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7.4.3 1-Carrier W-CDMA

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7.4.4 2-Carrier W-CDMA

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8. Package outline

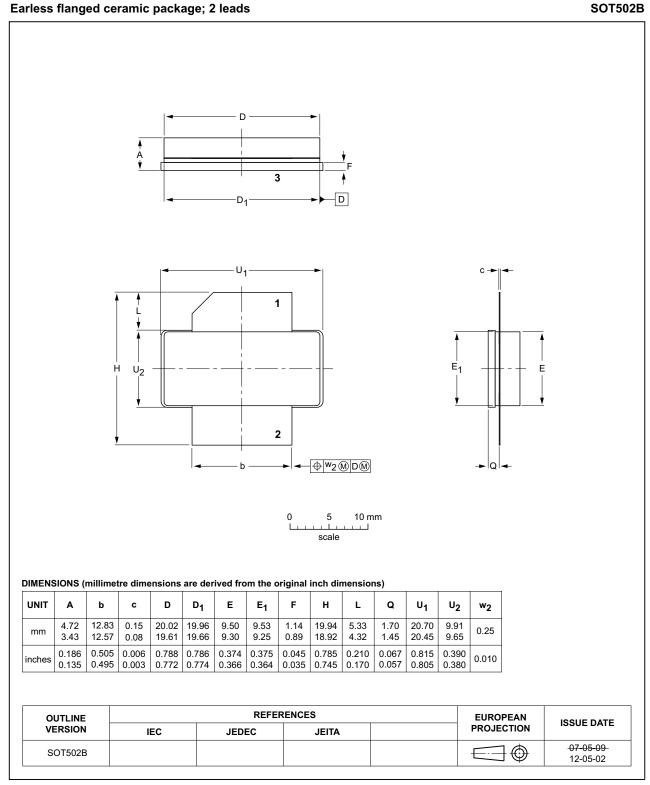


Fig 10. Package outline SOT502B

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9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

10. Abbreviations

Table 10. Abbre	Table 10. Abbreviations				
Acronym	Description				
3GPP	3rd Partnership Project				
CCDF	Complementary Cumulative Distribution Function				
CW	Continuous Wave				
DPCH	Dedicated Physical CHannel				
ESD	ElectroStatic Discharge				
LDMOS	Laterally Diffused Metal Oxide Semiconductor				
MTF	Median Time to Failure				
PAR	Peak-to-Average Ratio				
SMD	Surface Mounted Device				
VSWR	Voltage Standing Wave Ratio				
W-CDMA	Wideband Code Division Multiple Access				

11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes		
BLF8G27LS-100 v.2	20140305	Product data sheet	-	BLF8G27LS-100 v.1		
Modifications	• Table 7 on	<u>Table 7 on page 3</u> : table updated				
	Section 7	<u>Section 7 on page 3</u> : section added				
BLF8G27LS-100 v.1	20131219	Objective data sheet	-	-		

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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